

2010 AMERICAN CONTROL CONFERENCE

June 30 – July 2, 2010
Baltimore Marriot Waterfront
Baltimore, Maryland, USA
http://www.a2c2.org/conferences/acc2010/

July 2, 2010

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Title: Symbolic Dynamics of Wavelet Images for Pattern Identification Authors: Xin Jin, Shalabh Gupta, Kushal Mukherjee, Asok Ray

On behalf of the Operating and the Program Committees, it is my pleasure to inform you of your selection as a recipient of the Best Presentation in Session Award at the 2010 American Control Conference (ACC) held at the Baltimore Marriot Waterfront, Baltimore, Maryland, USA, June 30 – July 2, 2010.

The ACC is the annual meeting of American Automatic Control Council (AACC). Held under the auspices of AACC, the US National Member Organization of the International Federation of Automatic Control (IFAC), the ACC brings together people working in control, automation, and related areas from the American Institute of Aeronautics and Astronautics (AIAA), American Institute of Chemical Engineers (AIChE), Association of Iron and Steel Engineers (AISE), American Society of Civil Engineers (ASCE), American Society of Mechanical Engineers (ASME), Institute of Electrical and Electronics Engineers (IEEE), the International Society for Measurement and Control (ISA), and the Society for Computer Simulation (SCS).

Sincerely, Richard Braats

Richard D. Braatz, Ph.D. Program Chair, ACC 2010